

# MOSFET - N-Channel, QFET®

**600 V, 1.9 A, 4,7**  $\Omega$ 

# FQD2N60C / FQU2N60C

This N-Channel enhancement mode power MOSFET is produced using **onsemi**'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

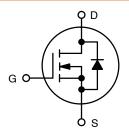
- 1.9 A, 600 V,  $R_{DS(on)} = 4.7 \Omega$  (Max.) @  $V_{GS} = 10$  V,  $I_D = 0.95$  A
- Low Gate Charge (Typ. 8.5 nC)
- Low Crss (Typ. 4.3 pF)
- 100% Avalanche Tested
- These Devices are Halid Free and are RoHS Compliant

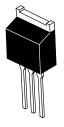
#### MAXIMUM RATINGS (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Rating	Value	Unit
V <sub>DSS</sub>	Drain-Source Voltage	600	V
I <sub>D</sub>	Drain Current – Continuous ( $T_C = 25^{\circ}C$ ) – Continuous ( $T_C = 100^{\circ}C$ )	1.9 1.14	Α
I <sub>DM</sub>	Drain Current - Pulsed (Note 1)	7.6	Α
V <sub>GSS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)	120	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)	1.9	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	4.4	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *	2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C	44 0.35	W W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	–55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purposes, 1/8" (from case for 5 seconds)	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
600 V	4.7 Ω @ 10 V	1.9 A



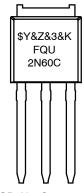


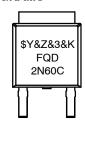


DPAK3 (IPAK) CASE 369AR

DPAK3 (TO-252 3 LD) CASE 369AS

#### **MARKING DIAGRAMS**





FQD2N60C,

FQU2N60C = Device Code \$Y = onsemi Logo &Z = Assembly Location &3 = Date Code

&K = Lot Run Traceability Code

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
FQD2N60CTM	DPAK3 (TO-252 3 LD) (Pb-Free)	2500 / Tape & Reel
FQU2N60CTU	DPAK3 (IPAK) (Pb-Free)	70 Units / Tube

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.87	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (minimum pad of 2 oz copper), Max.	110	°C/W
	Thermal Resistance, Junction-to-Ambient (* 1 in² pad of 2 oz copper), Max.	50	

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS		<u> </u>		<u></u>	
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	600	-	-	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C	-	-	10	
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	-	-	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V	-	-	-100	nA
ON CHARAC	CTERISTICS		-			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.95 A	-	3.6	4.7	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 0.95 A	-	5.0	-	S
DYNAMIC C	HARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,	_	180	235	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz	-	20	25	
C <sub>rss</sub>	Reverse Transfer Capacitance	7	-	4.3	5.6	
SWITCHING	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 2 \text{ A},$	-	9	28	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$ (Note 4)	-	25	60	
t <sub>d(off)</sub>	Turn-Off Delay Time	7	-	24	58	
t <sub>f</sub>	Turn-Off Fall Time	7	-	28	66	
$Q_g$	Total Gate Charge	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 2 A,	-	8.5	12	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V (Note 4)	-	1.3	-	
Q <sub>gd</sub>	Gate-Drain Charge	1	-	4.1	-	
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MA	XXIMUM RATINGS	-			
I <sub>S</sub>	Maximum Continuous Drain-Source Diod	e Forward Current	-	-	1.9	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		-	-	7.6	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.6 A	-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2 A,	-	230	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs	_	1.0	-	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product Product parametric performance is indicated in the Electrical Characteristics for the listed test condition performance may not be indicated by the Electrical Characteristics if operated under different conditions. 
1. Repetitive Rating: Pulse width limited by maximum junction temperature. 
2. L = 56 mH,  $I_{AS}$  = 2 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C. 
3.  $I_{SD} \le 2.0$  A, di/dt  $\le 200$ A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , Starting  $T_{J}$  = 25°C. 
4. Essentially independent of operating temperature.

#### **TYPICAL CHARACTERISTICS**

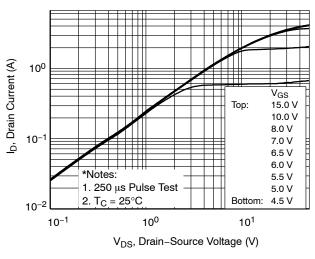


Figure 1. On-Region Characteristics

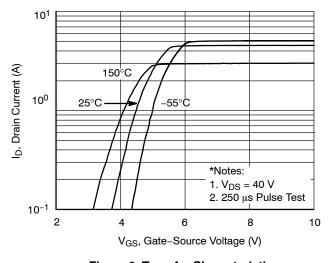


Figure 2. Transfer Characteristics

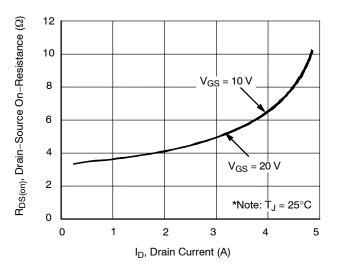


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

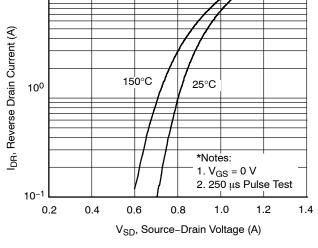


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

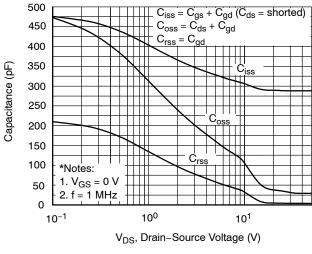


Figure 5. Capacitance Characteristics

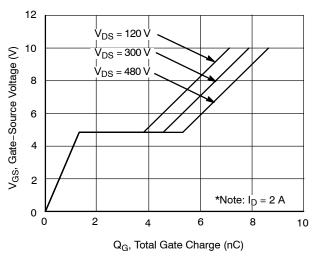
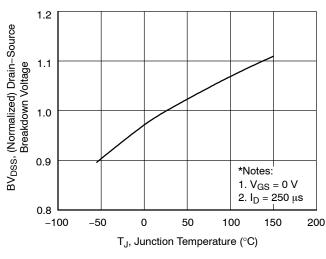


Figure 6. Gate Charge Characteristics

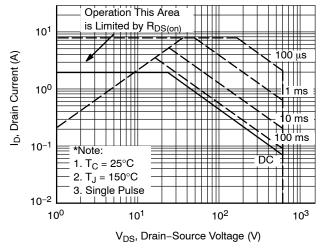
#### TYPICAL CHARACTERISTICS (continued)



3.0 R<sub>DS(ON)</sub>, (Normalized) Drain-Source 2.5 2.0 On-Resistance 1.5 1.0 \*Notes: 0.5 1.  $V_{GS} = 10 V$ 2.  $I_D = 0.95 A$ 0.0 -50 -10050 100 150 200 T<sub>J</sub>, Junction Temperature (°C)

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



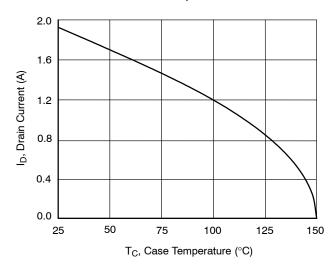


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

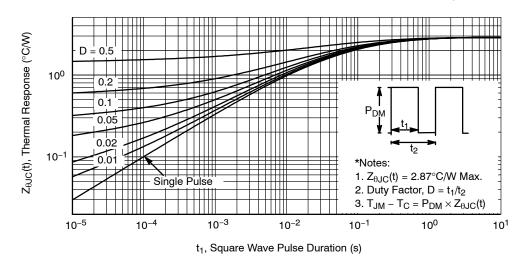


Figure 11. Transient Thermal Response Curve

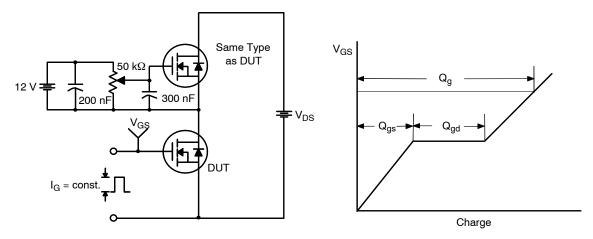


Figure 12. Gate Charge Test Circuit & Waveform

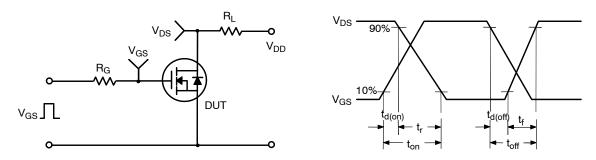


Figure 13. Resistive Switching Test Circuit & Waveforms

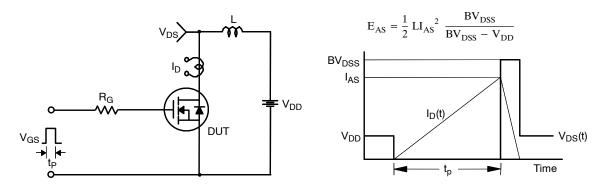
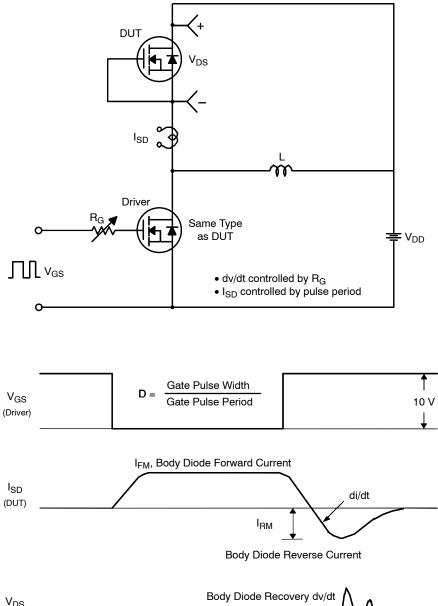


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



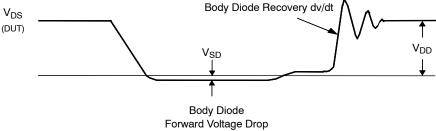
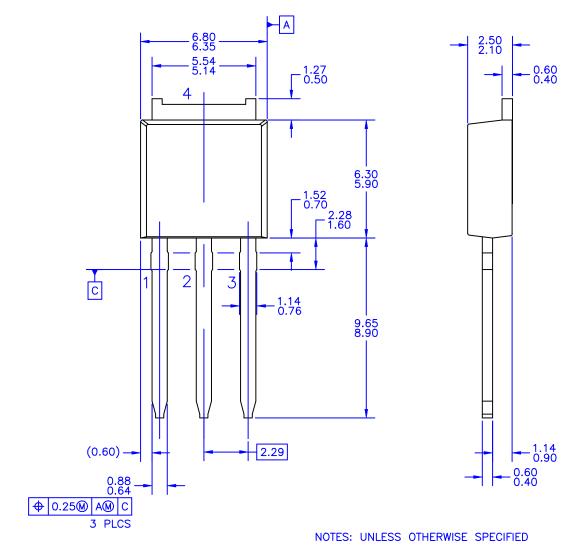


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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DPAK3 (IPAK) CASE 369AR ISSUE O

**DATE 30 SEP 2016** 





- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) THIS PACKAGE CONFORMS TO JEDEC, TO-251, ISSUE C, VARIATION AA, DATED SEP 1988.
- C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

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# **DPAK3 (TO-252 3 LD)**CASE 369AS **ISSUE A**

**DATE 28 SEP 2022** 

MILLIMETERS

0.64 0.77 0.89

NOM. MAX.

2.39 2.29

0.127

MIN.

2.18

0.00

NOTES: UNLESS OTHERWISE SPECIFIED

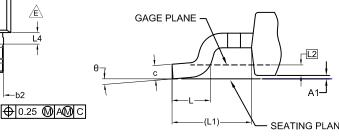
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- D) SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION.

  FOR DIODE PRODUCTS, L4 IS 0.25 MM MAX.

  F) DIMENSIONS ARE EXCLUSIVE OF BURRS,
- MOLD FLASH AND TIE BAR EXTRUSIONS.
- G) LAND PATTERN RECOMMENDATION IS BASED ON IPC7351A STD TO228P991X239-3N.

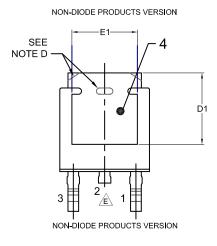
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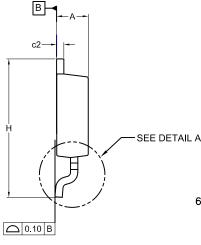
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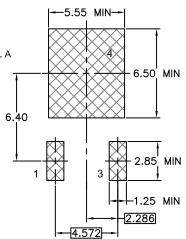


SEATING PLANE **DETAIL A** (ROTATED -90°) SCALE: 12X

D	0.04	0.77	0.09	
b2	0.76	0.95	1.14	
b3	5.21	5.34	5.46	
С	0.45	0.53	0.61	
c2	0.45	0.52	0.58	
D	5.97	6.10	6.22	
D1	5.21	_	-	
Е	6.35	6.54	6.73	
E1	4.32	_	-	
е	2.286 BSC			
e1	4.572 BSC			
Н	9.40	9.91	10.41	
L	1.40	1.59	1.78	
L1	2.90 REF			
L2	0.51 BSC			
L3	0.89	1.08	1.27	
L4		_	1.02	
θ	0°		10°	







#### **GENERIC MARKING DIAGRAM\***

XXXXXX XXXXXX **AYWWZZ** 

XXXX = Specific Device Code

= Assembly Location Α

WW = Work Week = Assembly Lot Code \*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

#### LAND PATTERN RECOMMENDATION

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

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